

# Visualization of Contamination with TXRF

## Total Reflection X-ray Fluorescence Spectrometer

### Advantage of TXRF

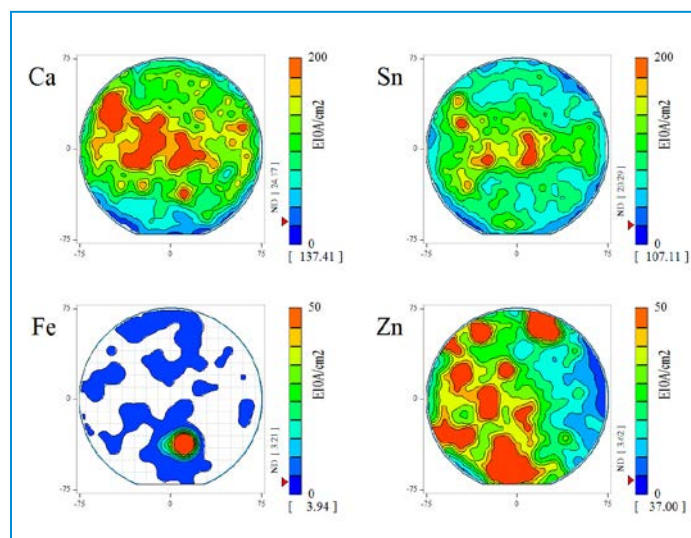


### Quick and Easy Measurements

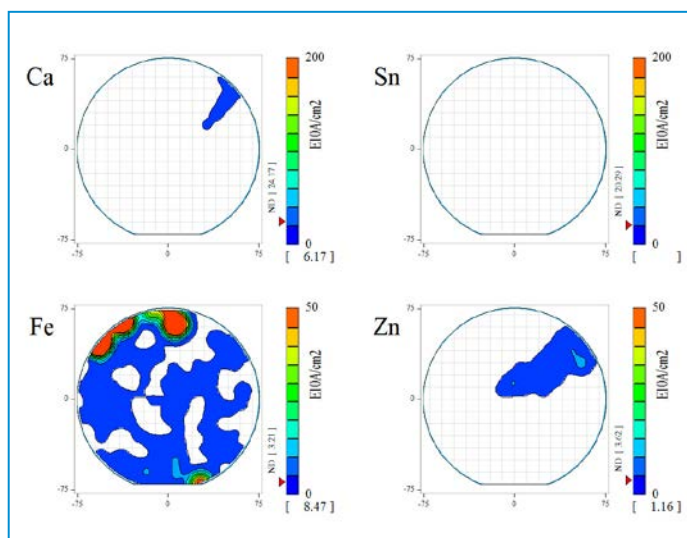
- No sample pre-treatment required
- Simple-to-maintain calibration
- Even a novice can measure contamination thanks to user-friendly software

### Sweeping-TXRF / ZEE-TXRF Applications

150 mm SiC Wafer - Process A



150 mm SiC Wafer - Process B



- TXRF provides entire wafer contamination mapping information
- Process A and B were run with different cleaning protocols by SiC wafer suppliers